



# March 1996

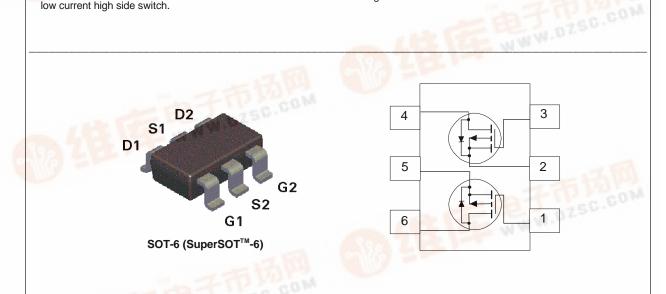
# NDC7003P Dual P-Channel Enhancement Mode Field Effect Transistor

### **General Description**

These dual P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. This product is particularly suited to low voltage applications requiring a low current high side switch.

# Features

- -0.34A, -50V.  $R_{DS(ON)}$ = 5 $\Omega$  @  $V_{GS}$ =-10V.
- High density cell design for low R<sub>DS(ON)</sub>.
- Proprietary SuperSOT<sup>TM</sup>-6 package design using copper lead frame for superior thermal and electrical capabilities.
- High saturation current.



Absolute	<b>Maximum Ratings</b> $T_A = 25^{\circ}C$ unless otherwise	se noted		-
Symbol	Parameter		NDC7003P	Units
V <sub>DSS</sub>	Drain-Source Voltage		-50	V
V <sub>GSS</sub>	Gate-Source Voltage - Continuous		-20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	-0.34	А
	- Pulsed		-1 WWW.DES	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	0.96	W
	17	(Note 1b)	0.9	
	一工市以	(Note 1c)	0.7	
T_,T <sub>stg</sub>	Operating and Storage Temperature Range	60.	-55 to 150	°C
THERMA	L CHARACTERISTICS			
R <sub>ØJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	130	°C/W
R <sub>øjc</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	60	°C/W

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	ARACTERISTICS	·			•		
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = -250 \mu\text{A}$		-50			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$				-1	μA
			T <sub>J</sub> = 125°C			-500	
	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	$V_{GS} = 20 \text{ V},  V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAI	RACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = -250 \ \mu.A$		-1	-2.5	-3.5	V
			T <sub>J</sub> = 125°C	-0.8	-2.2	-3	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -0.34 \text{ A}$			2.5	5	Ω
			T <sub>J</sub> = 125°C		4	10	
		$V_{GS} = -4.5 \text{ V}, I_{D} = -0.25 \text{ A}$			5.3	7.5	
l <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -10 \text{ V}, V_{DS} = -10 \text{ V}$		-1			Α
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -0.34 \text{ A}$			250		mS
DYNAMI	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			40		pF
C <sub>oss</sub>	Output Capacitance				13		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				4		pF
SWITCHI	NG CHARACTERISTICS (Note 2)	•					
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{\rm DD} = -25 \text{ V}, \ \text{I}_{\rm D} = -0.25 \text{ A},$ $V_{\rm GS} = -10 \text{ V}, \ \text{R}_{\rm GEN} = 25 \ \Omega$			14	20	nS
t <sub>r</sub>	Turn - On Rise Time				6	20	
t <sub>D(off)</sub>	Turn - Off Delay Time				13	20	
t <sub>f</sub>	Turn - Off Fall Time				6	20	]
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -25 V,			1.3		nC
Q <sub>gs</sub>	Gate-Source Charge	$I_{\rm D} = -0.34 \text{ A}, V_{\rm GS} = -10 \text{ V}$			0.23		nC
Q <sub>gd</sub>	Gate-Drain Charge				0.38		nC

ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise noted)						
Symbol	Parameter Conditions		Min	Тур	Max	Units
DRAIN-SOURCE DIODE CHARACTERISTICS						
I <sub>s</sub>	Maximum Continuous Source Current				-0.34	А
I <sub>SM</sub>	Maximum Pulse Source Current (Note 2)				-1	А
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \ \text{I}_{S} = -0.34 \text{ A} \text{ (Note 2)}$		-0.8	-1.2	V

Notes:

1. R<sub>gut</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>gut</sub> is guaranteed by design while R<sub>gut</sub> is determined by the user's board design.

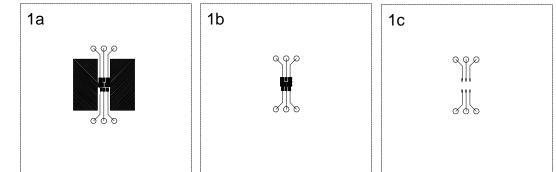
$$P_D(t) = \frac{T_T T_A}{R_{B,L} t} = \frac{T_T T_A}{R_{B,L} t R_{B,C} t} = I_D^2(t) \times R_{DS(ON)} \mathfrak{g}_{T_J}$$

Typical  $R_{_{BJA}}$  for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

a. 130°C/W when mounted on a 0.125  $\mbox{in}^2$  pad of 2oz cpper.

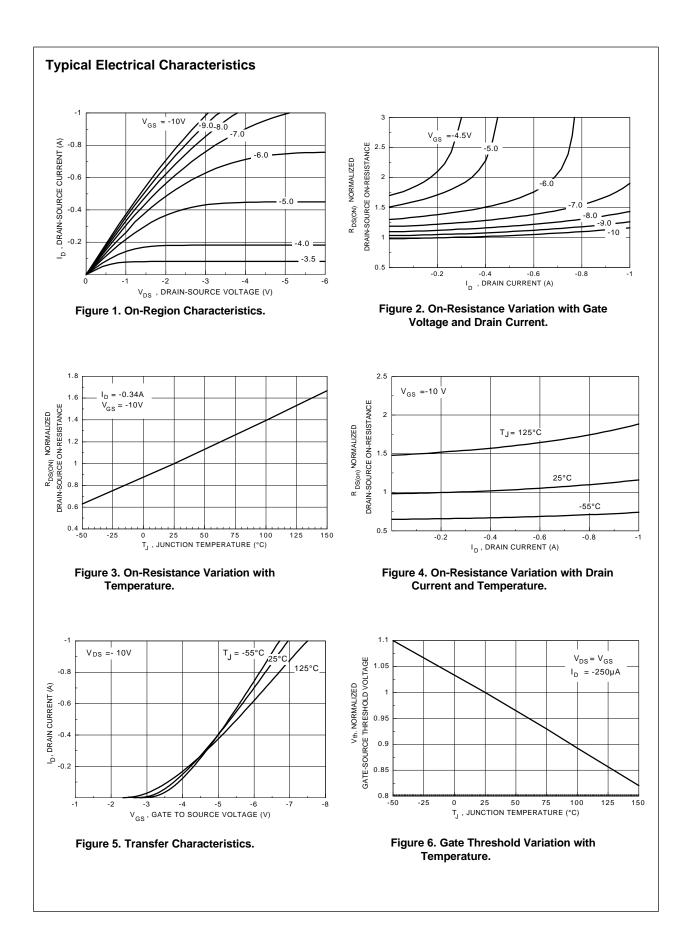
b.  $140^{\circ}\mbox{C/W}$  when mounted on a 0.005  $\mbox{in}^2$  pad of 2oz cpper.

c. 180°C/W when mounted on a 0.0015  $\mbox{in}^2$  pad of 2oz cpper.



Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2.0%.



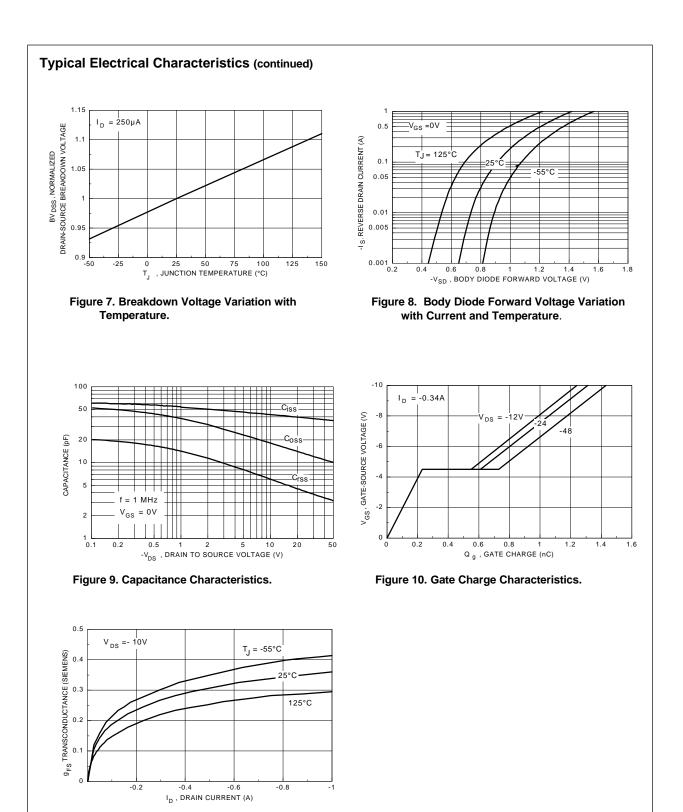
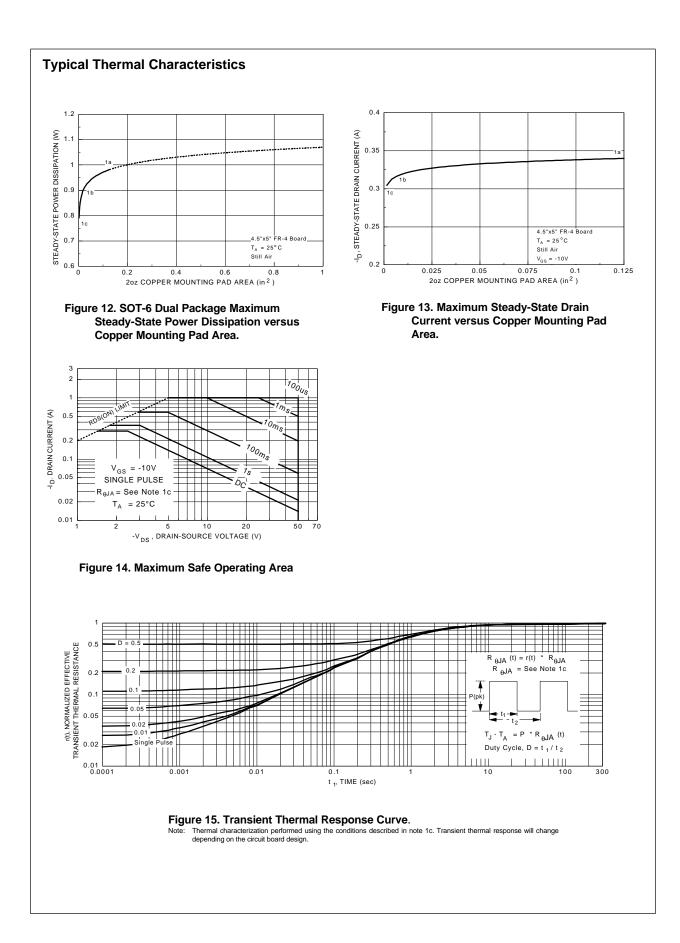
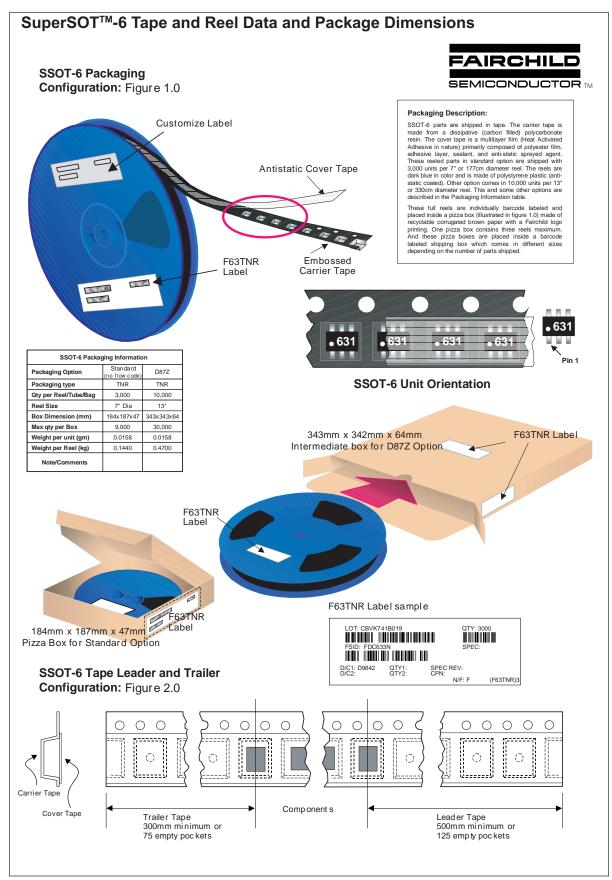
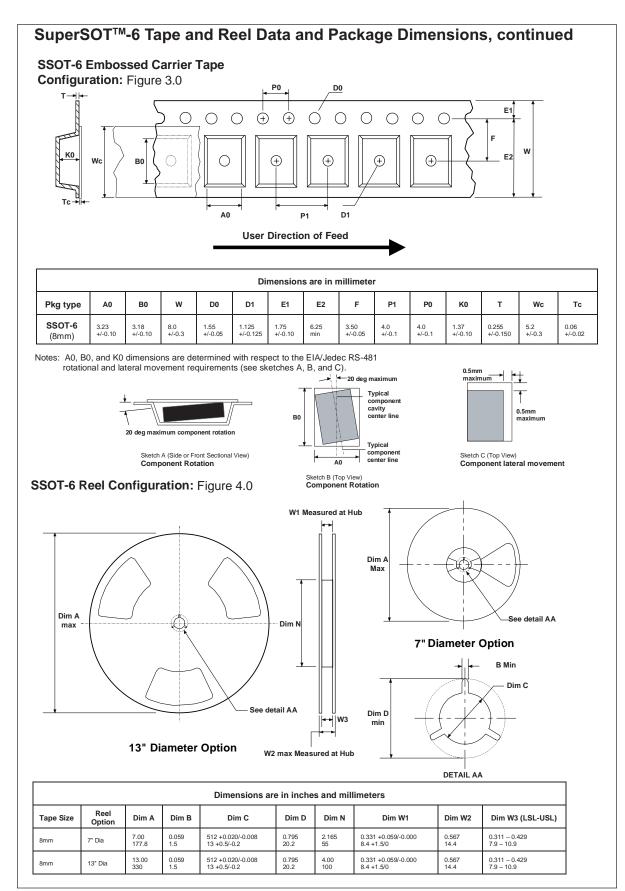
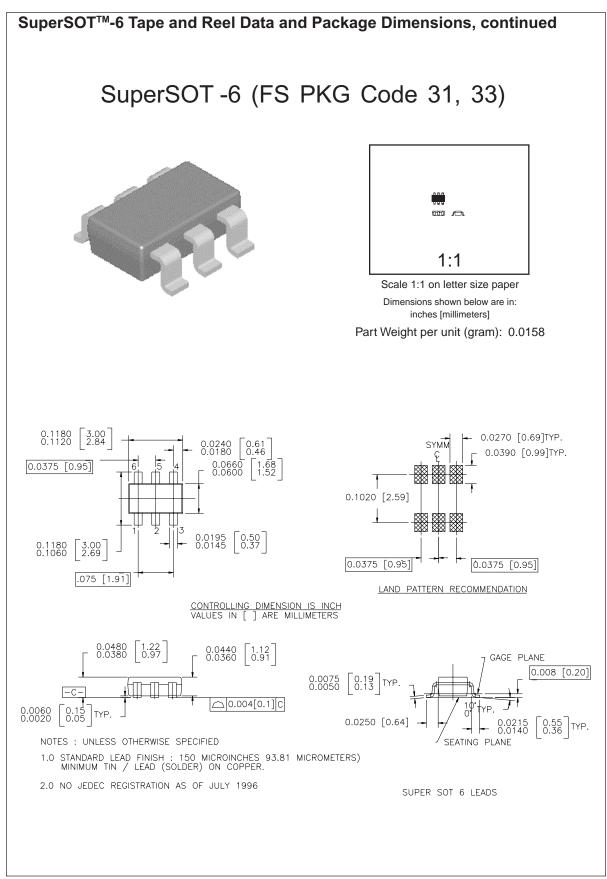


Figure 11. Transconductance Variation with Drain Current and Temperature.









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